



1042/Pre
K
Leure
PATENT 7-8-98

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of:

Wayne A. Bonin

Serial No.: 08/965,332

Examiner D. Larkin

Filed: November 6, 1997

Group Art Unit 2605

For: APPARATUS FOR MICROINDENTATION HARDNESS TESTING AND
SURFACE IMAGING INCORPORATING A MULTI-PLATE
CAPACITOR SYSTEM

Docket No.: 55463/101/103

Assistant Commissioner for Patents
Washington, D.C. 20231

Sir:

PRELIMINARY AMENDMENT

In the Claims

Rewrite claim 41 as follows:

K1
1 ~~41~~. (Amended) In a [A] scanned probe microscope apparatus
having a probe and a scanning head operably arranged for measuring
surface properties of a sample, the apparatus improvement
comprising:

a high precision capacitance sensor having a pick-up
plate movably mounted relative to a drive plate;

means for transmitting force between an object remote
from the pick-up plate and the pick-up plate; and

means responsive to the position of the pick-up plate
relative to the drive plate for providing an output signal
proportional to the relative position.